

August 2001 Revised September 2001

# **FSTU3253**

# **Dual 4:1 Multiplexer/Demultiplexer Bus Switch** with -2V Undershoot Protection

# **General Description**

The Fairchild Switch FSTU3253 is a dual 4:1 high-speed CMOS TTL-compatible multiplexer/demultiplexer bus switch. The low On Resistance of the switch allows inputs to be connected to outputs without adding propagation delay or generating additional ground bounce noise.

When  $\overline{\text{OE}}$  is LOW,  $S_0$  and  $S_1$  connect the A Port to the selected B Port output. When  $\overline{\text{OE}}$  is HIGH, the switch is OPEN and a high-impedance state exists between the two ports.

The A and B Ports are protected against undershoot to support an extended range to 2.0V below ground. Fairchild's integrated Undershoot Hardened Circuit (UHCTM) senses undershoot at the I/O and responds by preventing voltage differentials from developing and turning the switch on.

## **Features**

- Undershoot hardened to -2.0V
- $\blacksquare$  4 $\Omega$  switch connection between two ports
- Minimal propagation delay through the switch
- Low I<sub>CC</sub>
- Zero bounce in flow-through mode
- Control inputs compatible with TTL level
- See application note AN-5008 and AN-5021 for details on undershoot

# **Ordering Code:**

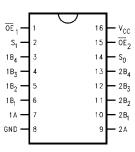
Order Number	Package Number	Package Description
FSTU3253M	M16A	16-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150" Narrow
FSTU3253QSC	MQA16	16-Lead Quarter Size Outline Package (QSOP), JEDEC MO-137, 0.150" Wide
FSTU3253MTC	MTC16	16-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide

Device also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.

# FSTU3253

# **Logic Diagram**

# **Connection Diagram**



# **Pin Descriptions**

Pin Name	Description
$\overline{OE}_1$ , $\overline{OE}_2$	Bus Switch Enables
S <sub>0</sub> , S <sub>1</sub>	Select Inputs
A	Bus A
B <sub>1</sub> , B <sub>2</sub> , B <sub>3</sub> , B <sub>4</sub>	Bus B

# **Truth Table**

S <sub>1</sub>	S <sub>0</sub>	OE <sub>1</sub>	OE <sub>2</sub>	Function
Х	Х	Н	Х	Disconnect 1A
Х	Χ	X	Н	Disconnect 2A
L	L	L	L	$A = B_1$
L	Н	L	L	$A = B_2$
Н	L	L	L	$A = B_3$
Н	Н	L	L	$A = B_4$

# **Absolute Maximum Ratings**(Note 1)

# Recommended Operating Conditions (Note 3)

 $\begin{array}{ll} \mbox{Power Supply Operating ($V_{CC}$)} & 4.0\mbox{V to } 5.5\mbox{V} \\ \mbox{Input Voltage ($V_{IN}$)} & 0\mbox{V to } 5.5\mbox{V} \\ \mbox{Output Voltage ($V_{OUT}$)} & 0\mbox{V to } 5.5\mbox{V} \\ \end{array}$ 

Input Rise and Fall Time  $(t_r, t_f)$ 

Note 1: The Absolute Maximum Ratings are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the Electrical Characteristics tables are not guaranteed at the absolute maximum rating. The Recommended Operating Conditions tables will define the conditions for actual device operation.

**Note 2:** The input and output negative voltage ratings may be exceeded if the input and output diode current ratings are observed.

Note 3: Unused control inputs must be held HIGH or LOW. They may not float

### **DC Electrical Characteristics**

		v <sub>cc</sub>	T <sub>A</sub> = -40 °C to +85 °C					
Symbol	Parameter	(V)	Min	Typ (Note 4)	Max	Units	Conditions	
V <sub>IK</sub>	Clamp Diode Voltage	4.5			-1.2	V	$I_{IN} = -18 \text{ mA}$	
V <sub>IH</sub>	High Level Input Voltage	4.0-5.5	2.0			V		
V <sub>IL</sub>	Low Level Input Voltage	4.0-5.5			0.8	V		
I	Input Leakage Current	5.5			±1.0	μΑ	$0 \le V_{IN} \le 5.5V$	
		0			10	μΑ	V <sub>IN</sub> = 5.5V	
l <sub>OZ</sub>	OFF-STATE Leakage Current	5.5			±1.0	μΑ	0 ≤ A, B ≤ V <sub>CC</sub>	
R <sub>ON</sub>	Switch On Resistance	4.5		4	7	Ω	V <sub>IN</sub> = 0V, I <sub>IN</sub> = 64 mA	
	(Note 5)	4.5		4	7	Ω	V <sub>IN</sub> = 0V, I <sub>IN</sub> = 30 mA	
		4.5		8	15	Ω	V <sub>IN</sub> = 2.4V, I <sub>IN</sub> = 15 mA	
		4.0		11	20	Ω	V <sub>IN</sub> = 2.4V, I <sub>IN</sub> = 15 mA	
Icc	Quiescent Supply Current	5.5			3	μΑ	V <sub>IN</sub> = V <sub>CC</sub> or GND, I <sub>OUT</sub> = 0	
ΔI <sub>CC</sub>	Increase in I <sub>CC</sub> per Input	5.5			2.5	mA	One Input at 3.4V	
							Other Inputs at V <sub>CC</sub> or GND	
V <sub>IKU</sub>	Voltage Undershoot	5.5			-2.0	V	0.0 mA ≥ I <sub>IN</sub> ≥ −50 mA	
							OE = 5.5V	

Note 4: Typical values are at  $V_{CC} = 5.0V$  and  $T_A = +25$ °C

Note 5: Measured by the voltage drop between A and B pins at the indicated current through the switch. On resistance is determined by the lower of the voltages on the two (A or B) pins.

# **AC Electrical Characteristics**

		$T_A = -40$ °C to +85 °C $C_L = 50$ pF, RU = RD = $500\Omega$						Figure	
Symbol	Parameter	V <sub>CC</sub> = 4.5 - 5.5V		$V_{CC} = 4.0V$		Units	Conditions	Number	
		Min	Max	Min	Max				
t <sub>PHL</sub> , t <sub>PLH</sub>	Propagation Delay Bus to Bus (Note 6)		0.25		0.25	ns	V <sub>I</sub> = OPEN	Figures	
	Propagation Delay, Select to Bus A	0.5	5.7		6.2	113	VI - OI LIV	2, 3	
t <sub>PZH</sub> , t <sub>PZL</sub>	Output Enable Time, Select to Bus B	0.5	5.7		6.3	ns	$V_I = 7V$ for $t_{PZL}$	Figures	
	Output Enable Time, I <sub>OE</sub> to Bus A, B	0.5	4.9		5.4	115	$V_I = OPEN$ for $t_{PZH}$	2, 3	
t <sub>PHZ</sub> , t <sub>PLZ</sub>	Output Disable Time, Select to Bus B	0.5	6.2		6.3	ns	$V_I = 7V$ for $t_{PLZ}$	Figures	
	Output Disable Time, I <sub>OE</sub> to Bus A, B	0.5	6.0		6.1	115	$V_I = OPEN \text{ for } t_{PHZ}$	2, 3	

Note 6: This parameter is guaranteed by design but is not tested. The bus switch contributes no propagation delay other than the RC delay of the typical On resistance of the switch and the 50pF load capacitance, when driven by an ideal voltage the source (zero output impedance).

# Capacitance (Note 7)

Sy	Symbol Parameter		Parameter Typ		Units	Conditions
C <sub>IN</sub>		Control Pin Input Capacitance	3		pF	V <sub>CC</sub> = 5.0V
C <sub>I/O</sub>	A Port	Input/Output Capacitance	13		pF	$V_{CC}$ , $\overline{OE} = 5.0V$
	B Port		5		pF	VCC, OL = 3.0 V

Note 7: T<sub>A</sub> = +25°C, f = 1 MHz, Capacitance is characterized but not tested.

# **Undershoot Characteristic** (Note 8)

Symbol	Parameter	Min	Тур	Max	Units	Conditions
V <sub>OUTU</sub>	Output Voltage During Undershoot	2.5	V <sub>OH</sub> - 0.3		V	Figure 1

Note 8: This test is intended to characterize the device's protective capabilities by maintaining output signal integrity during an input transient voltage undershoot event.

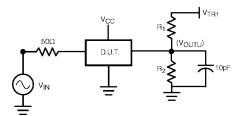
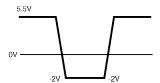


FIGURE 1.

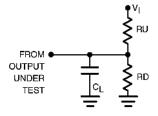
# **Device Test Conditions**

Parameter	Value	Units
V <sub>IN</sub>	see Waveform	V
$R_1 = R_2$	100K	Ω
V <sub>TRI</sub>	11.0	V
V <sub>CC</sub>	5.5	V

# Transient Input Voltage (V<sub>IN</sub>) Waveform



# **AC Loading and Waveforms**



Note: Input driven by 50  $\Omega$  source terminated in 50  $\Omega$  Note:  $C_L$  includes load and stray capacitance Note: Input PRR = 1.0 MHz,  $t_W$  = 500 ns

FIGURE 2. AC Test Circuit

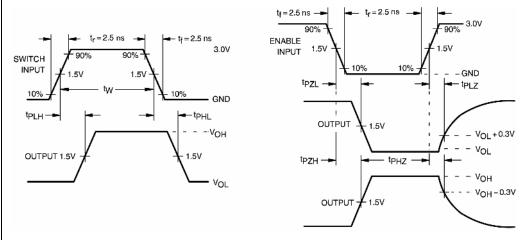
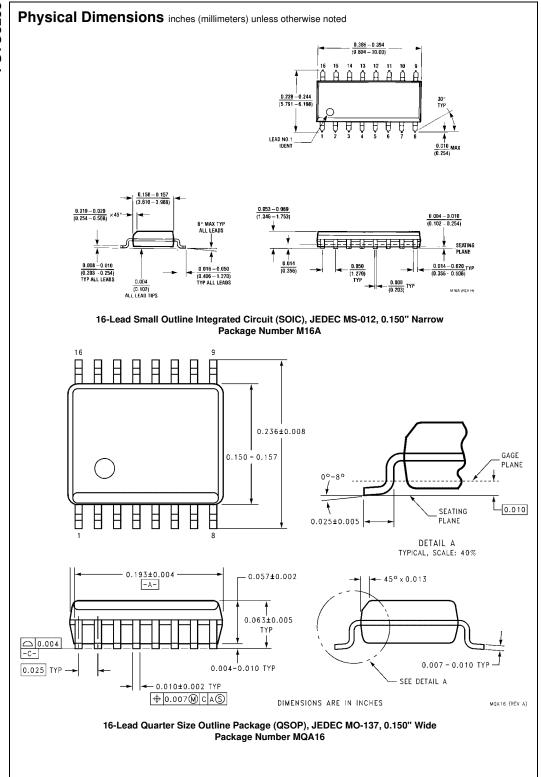
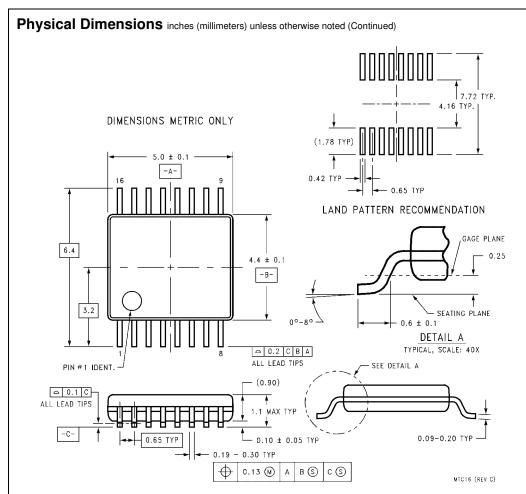


FIGURE 3. AC Waveforms





16-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide Package Number MTC16

## **Technology Description**

The Fairchild Switch family derives from and embodies Fairchild's proven switch technology used for several years in its 74LVX3L384 (FST3384) bus switch product.

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